

## DESCRIPTION


The RH108A is a precision operational amplifier particularly well-suited for high source impedance applications requiring low offset and bias currents and low power consumption.

The wafer lots are processed to Linear Technology's in-house Class S flow to yield circuits usable in stringent military applications.

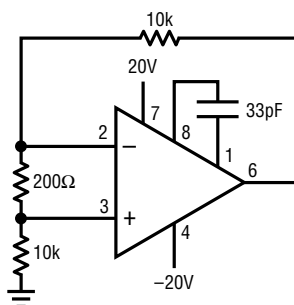
For complete electrical specifications, performance curves and applications information, see the LM108A/LM108 data sheet.

## ABSOLUTE MAXIMUM RATINGS

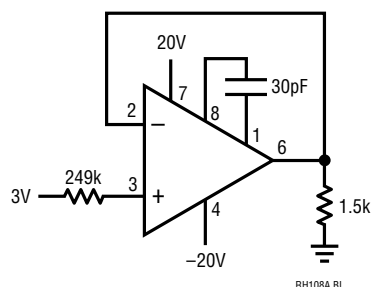
Supply Voltage .....	$\pm 20\text{V}$
Differential Input Current (Note 1) .....	$\pm 10\text{mA}$
Input Voltage (Note 2) .....	$\pm 15\text{V}$
Output Short-Circuit Duration .....	Indefinite
Operating Temperature Range .....	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
Storage Temperature Range .....	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$
Lead Temperature (Soldering, 10 sec) .....	$300^{\circ}\text{C}$

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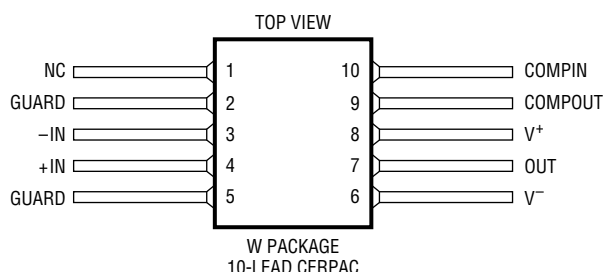
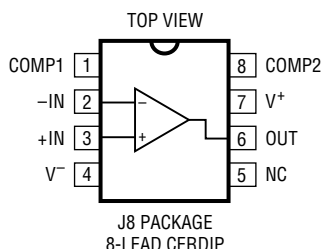
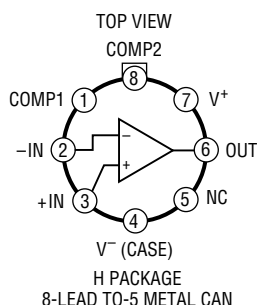
## BURN-IN CIRCUIT



OR



## PACKAGE INFORMATION



**TABLE 1: ELECTRICAL CHARACTERISTICS** (Preirradiation) (Note 4)

SYMBOL	PARAMETER	CONDITIONS	NOTES	T <sub>A</sub> = 25°C			SUB-GROUP	-55°C T <sub>A</sub> 125°C			SUB-GROUP	UNITS
				MIN	TYP	MAX		MIN	TYP	MAX		
V <sub>OS</sub>	Input Offset Voltage					0.5	1			1.0	2,3	mV
$\frac{V_{OS}}{\text{Temp}}$	Average Tempco of Offset Voltage		3							5.0		μV/°C
I <sub>OS</sub>	Input Offset Current					0.2	1			0.4	2,3	nA
$\frac{I_S}{\text{Temp}}$	Average Tempco of Offset Current		3							2.5		pA/°C
I <sub>B</sub>	Input Bias Current					2.0	1			3.0	2,3	nA
A <sub>VOL</sub>	Large-Signal Voltage Gain	V <sub>S</sub> = ±15V, V <sub>OUT</sub> = ±10V R <sub>L</sub> 10k		80			4	40			5,6	V/mV
CMRR	Common Mode Rejection Ratio			96			1	96			2,3	dB
PSRR	Power Supply Rejection Ratio			96			1	96			2,3	dB
	Input Voltage Range	V <sub>S</sub> = ±15V	3	±13.5				±13.5				V
V <sub>OUT</sub>	Output Voltage Swing	V <sub>S</sub> = ±15V, R <sub>L</sub> = 10k		±13			4	±13			5,6	V
R <sub>IN</sub>	Input Resistance		3	30								M
I <sub>S</sub>	Supply Current	(Note 6)				0.6	1			0.4	2	mA

**TABLE 1A: ELECTRICAL CHARACTERISTICS** (Postirradiation) (Note 5)

SYMBOL	PARAMETER	CONDITIONS	NOTES	10KRAD(Si)		20KRAD(Si)		50KRAD(Si)		80KRAD(Si)		UNITS
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
V <sub>OS</sub>	Input Offset Voltage				0.5		0.5		0.5		1.0	mV
I <sub>OS</sub>	Input Offset Current				0.2		0.2		0.2		0.2	nA
I <sub>B</sub>	Input Bias Current				±2.0		±2.0		±2.0		±4.0	nA
A <sub>VOL</sub>	Large-Signal Voltage Gain	V <sub>S</sub> = ±15V, V <sub>OUT</sub> = ±10V R <sub>L</sub> 10k			98		98		90		86	dB
CMRR	Common Mode Rejection Ratio				96		96		84		70	dB
PSRR	Power Supply Rejection Ratio				96		96		84		70	dB
	Input Voltage Range		3	±13.5		±13.5		±13.5		±13.5		V
V <sub>OUT</sub>	Output Voltage Swing			±13		±13		±13		±13		V
R <sub>IN</sub>	Input Resistance		3	30		30		30		30		M
I <sub>S</sub>	Supply Current				0.6		0.6		0.6		0.6	mA

**Note 1:** Differential input voltages greater than 1V will cause excessive current to flow through the input diodes unless limiting resistance is used.

**Note 2:** For supply voltages less than ±15V, the maximum input voltage is equal to the supply voltage.

**Note 3:** Guaranteed by design, characterization or correlation to other tested parameters.

**Note 4:** ±5V V<sub>S</sub> ±20V unless otherwise noted.

**Note 5:** V<sub>S</sub> = ±15V, V<sub>CM</sub> = 0V, T<sub>A</sub> = 25°C unless otherwise noted.

**Note 6:** 25°C T<sub>A</sub> 125°C.

## TABLE 2: ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUP
Final Electrical Test Requirements (Method 5004)	1*,2,3,4,5,6
Group A Test Requirements (Method 5005)	1,2,3,4,5,6
Group C and D End Point Electrical Parameters (Method 5005)	1

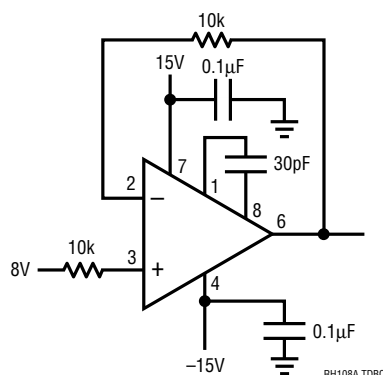
\* PDA Applies to subgroup 1. See PDA Test Notes.

### PDA Test Notes

The PDA is specified as 5% based on failures from group A, subgroup 1, tests after cooldown as the final electrical test in accordance with method 5004 of MIL-STD-883 Class B. The verified failures (including Delta parameters) of group A, subgroup 1, after burn-in divided by the total number of devices submitted for burn-in in that lot shall be used to determine the percent for the lot.

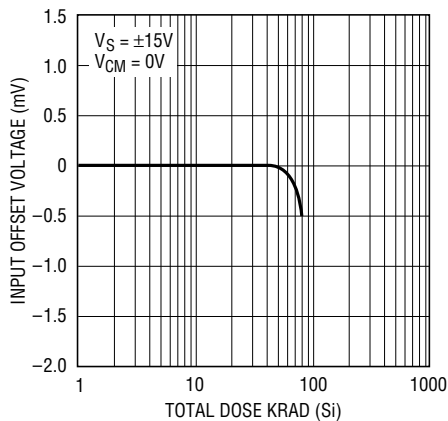
Linear Technology Corporation reserves the right to test to tighter limits than those given.

## TOTAL DOSE BIAS CIRCUIT



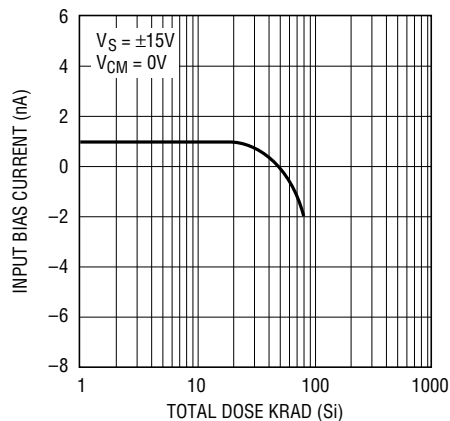
# TYPICAL PERFORMANCE CHARACTERISTICS

### Input Offset Voltage



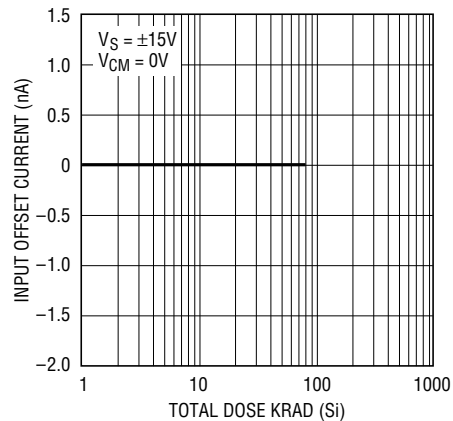
RH108A G01

### Input Bias Current



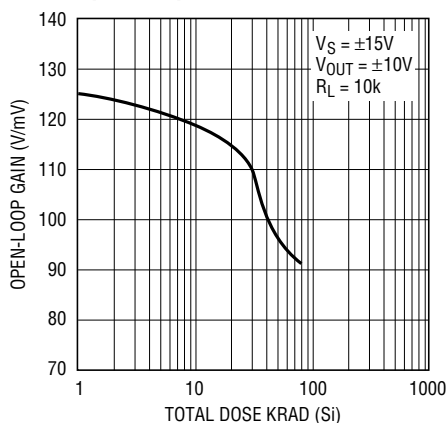
RH108A G02

### Input Offset Current



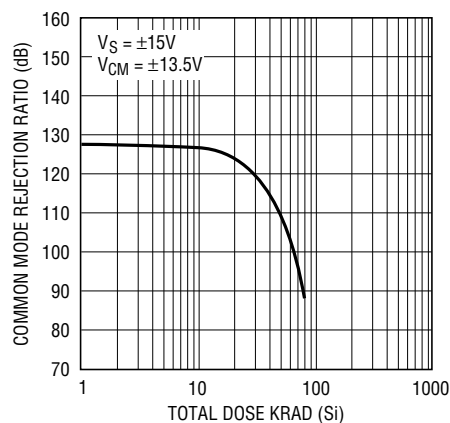
RH108A G03

### Open-Loop Gain



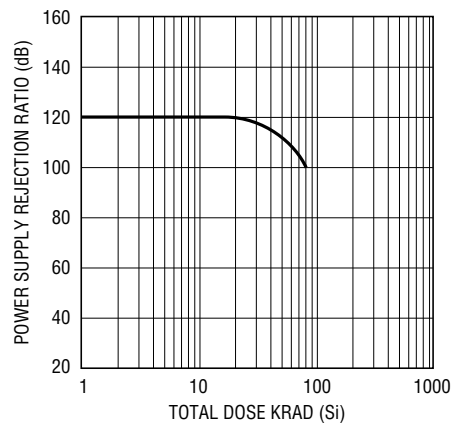
RH108A G04

### Common Mode Rejection Ratio



RH108A G05

### Power Supply Rejection Ratio



RH108A G06